

IC 燒錄座 QFN8 轉 DIP8 測試座 WSON8 MLF8 DFN6X8-8L(1.27) 8*6 適配座

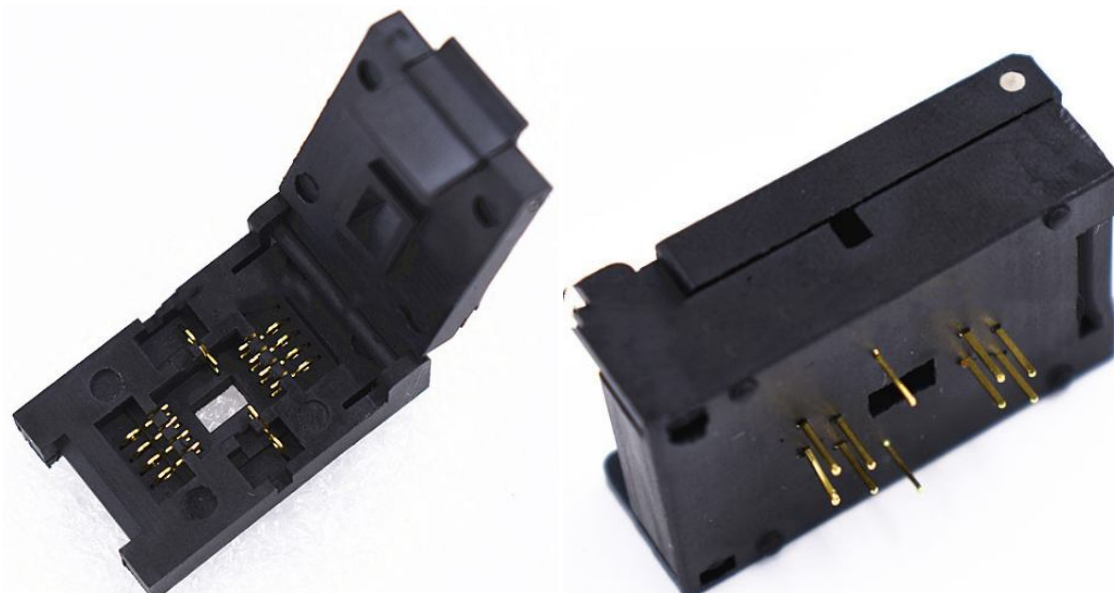
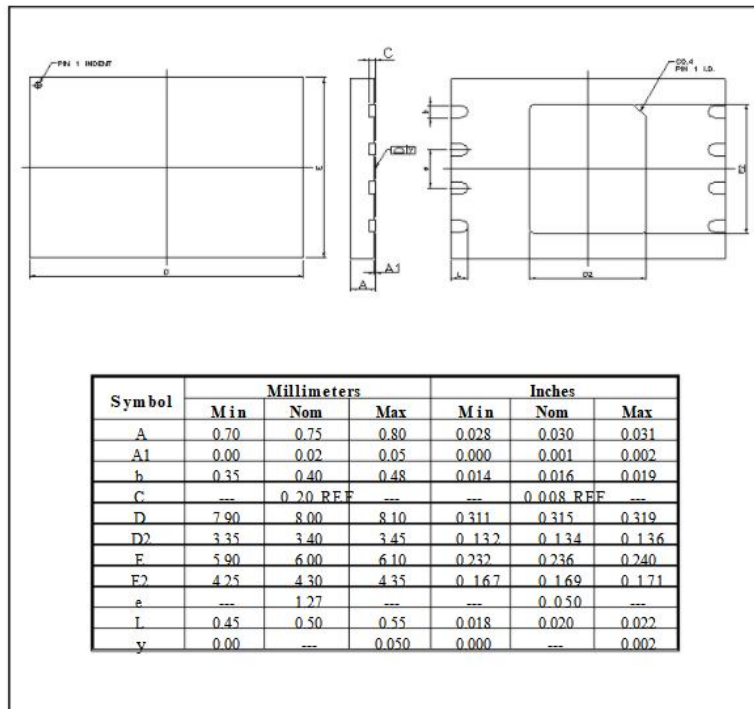
IC 燒錄座 QFN8 轉 DIP8 測試座 WSON8 MLF8 QFN8 6x8 8*6 DFN8 適配座

適配 IC 封裝：QFN/WSON/DFN

腳位：8PIN

尺寸：6*8mm

間距：1.27mm



老化測試座 DFN2X3-8L(0.5) 鍍金 高溫 老化座 燒錄 夾具插座

老化測試座 DFN2X3-6L(0.5)鍍金 高溫 老化座 燒錄 夾具插座直銷

測試座型號：DFN2X3-6L(0.5)翻蓋式

IC 整體寬度：2.0x3.0mm

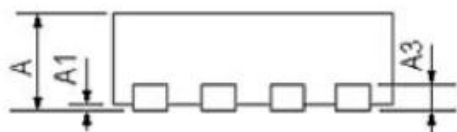
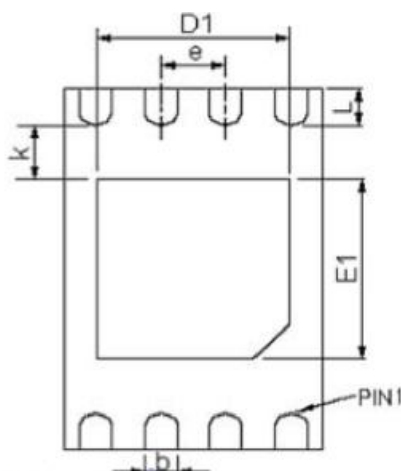
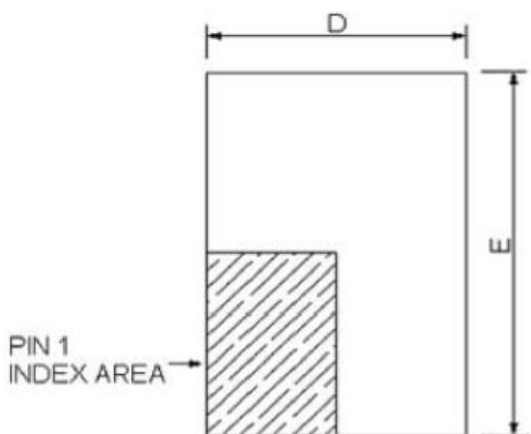
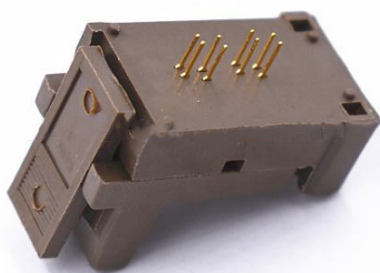
IC 間距：0.5mm

IC 封裝：DFN2X3-6L(0.5)

高低溫範圍：-45°C ~ +175°C

DFN2X3-8L(0.5)老化测试座

测试座型号：DFN2X3-6L(0.5)翻蓋式
 IC 整体宽度：2.0x3.0mm
 IC 间距：0.5mm
 IC 封装：DFN2X3-6L(0.5)
 高低温范围：-45°C ~ +175°C



SIDE VIEW

PKG.	DIMENSIONS (MM)	
SYMBOL	MIN.	MAX
A	0.700	0.800
A1	0.000	0.500
A3	0.203REF	
D	1.924	2.076
E	2.924	3.076
D1	1.400	1.600
E1	1.400	1.600
k	0.200MIN	
b	0.200	0.300
e	0.500TYP	
L	0.224	0.376

Note:
 Ref: JEDEC MO-229